


<b>Search Notes</b>  	<b>Application/Control No.</b>  10065159	<b>Applicant(s)/Patent Under Reexamination</b>  TKACZYK ET AL.
	<b>Examiner</b>  Nguyen, Tran N	<b>Art Unit</b>  3626

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
705	2-3 (cursory with keyword)	05/30/2007	Nguyen, Tran N

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
705/7 (consulted B. Van Doren A.U. 3623)	03/07/2007	Nguyen, Tran N
US patent database (EAST)	05/30/2007	Nguyen, Tran N
Reviewed IFW record of 09/655,667	05/30/2007	Nguyen, Tran N
Please see attachment for Examiner's search strategy.		

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>